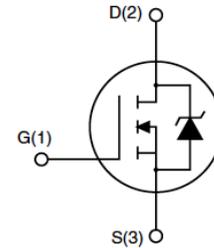


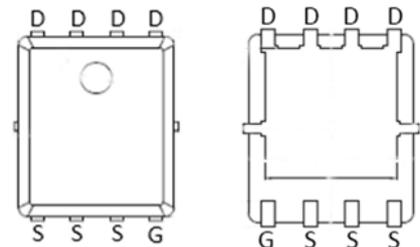
## Feature

- 60V,150A  
 $R_{DS(ON)} < 2.3m\Omega @ V_{GS}=10V$  (TYP:1.9m $\Omega$ )  
 $R_{DS(ON)} < 3.5m\Omega @ V_{GS}=4.5V$  (TYP:3.0m $\Omega$ )
- Split Gate Trench Technology
- Lead free product is acquired
- Excellent  $R_{DS(ON)}$  and Low Gate Charge
- $T_{jmax}=175^{\circ}C$
- AEC-Q101 qualified



## Application

- PWM applications
- Load Switch
- Power management



PDFN5X6

## Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity (PCS)
G022N06G	APG022N06G-AU	PDFN5X6	-	-	5000

## ABSOLUTE MAXIMUM RATINGS ( $T_a=25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current ( $T_c=25^{\circ}C$ )	$I_D$	150	A
Continuous Drain Current ( $T_c=100^{\circ}C$ )	$I_D$	100	A
Pulsed Drain Current <sup>(1)</sup>	$I_{DM}$	450	A
Single Pulsed Avalanche Energy <sup>(2)</sup>	$E_{AS}$	520	mJ
Power Dissipation	$P_D$	168	W
Thermal Resistance from Junction to Case	$R_{\theta JC}$	0.89	$^{\circ}C/W$
Thermal Resistance from Junction to Ambient	$R_{\theta JA}$	45	$^{\circ}C/W$
Junction Temperature	$T_J$	175	$^{\circ}C$
Storage Temperature	$T_{STG}$	-55~ +175	$^{\circ}C$

**MOSFET ELECTRICAL CHARACTERISTICS(T<sub>a</sub>=25°C unless otherwise noted)**

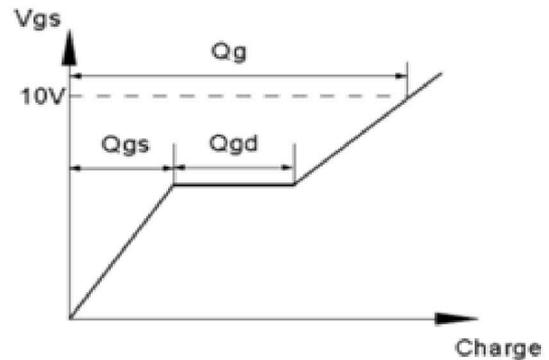
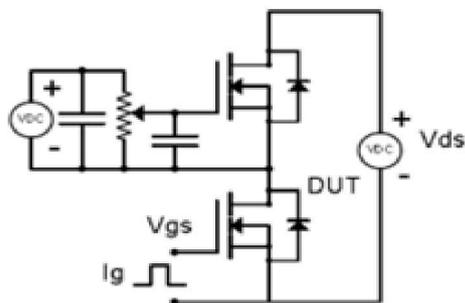
Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Static Characteristics</b>						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> =250μA	60	-	-	V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =60V, V <sub>GS</sub> = 0V	-	-	1	μA
Gate-body leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA
Gate threshold voltage <sup>(3)</sup>	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.5	2.0	3.0	V
Drain-source on-resistance <sup>(3)</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	1.9	2.3	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A	-	3.0	3.5	mΩ
Forward Threshold Voltage	g <sub>fs</sub>	V <sub>DS</sub> =5V, I <sub>D</sub> =20A	-	75	-	S
<b>Dynamic characteristics</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f =100KHz	-	6052	-	pF
Output Capacitance	C <sub>oss</sub>		-	1470	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	185	-	
<b>Switching characteristics</b>						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =30V, I <sub>D</sub> =25A, V <sub>GS</sub> =10V, R <sub>G</sub> =2Ω	-	8	-	ns
Turn-on rise time	t <sub>r</sub>		-	15	-	
Turn-off delay time	t <sub>d(off)</sub>		-	55	-	
Turn-off fall time	t <sub>f</sub>		-	25	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =30V, I <sub>D</sub> =25A, V <sub>GS</sub> =10V	-	110	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	20	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	21	-	
Reverse Recovery Chrage	Q <sub>rr</sub>	I <sub>F</sub> =20A, di/dt=100A/us		100		nC
Reverse Recovery Time	T <sub>rr</sub>	I <sub>F</sub> =20A, di/dt=100A/us		72		ns
<b>Source-Drain Diode characteristics</b>						
Diode Forward voltage <sup>(3)</sup>	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =10A	-	-	1.2	V
Diode Forward current <sup>(4)</sup>	I <sub>S</sub>		-	-	150	A

**Notes:**

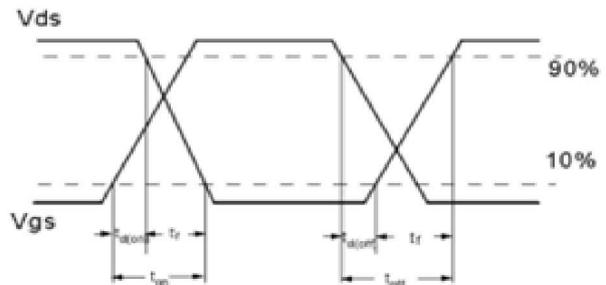
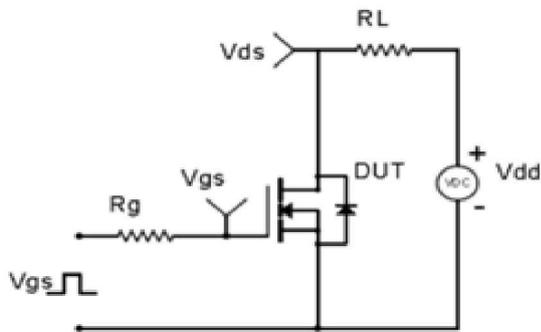
1. Repetitive Rating: pulse width limited by maximum junction temperature
2. EAS Condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=48V, R<sub>G</sub>=25 Ω, L=0.5Mh
3. Pulse Test: pulse width≤300μs, duty cycle≤2%
4. Surface Mounted on FR4 Board, t≤10 sec

**Test Circuit & Waveform**

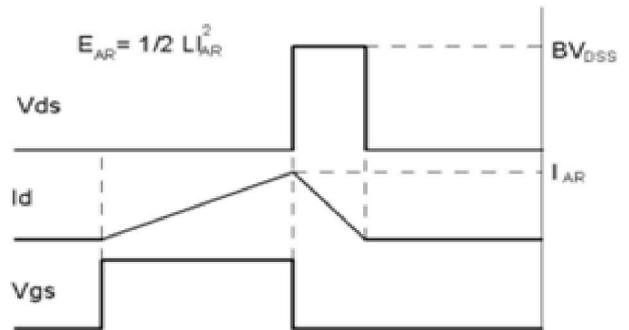
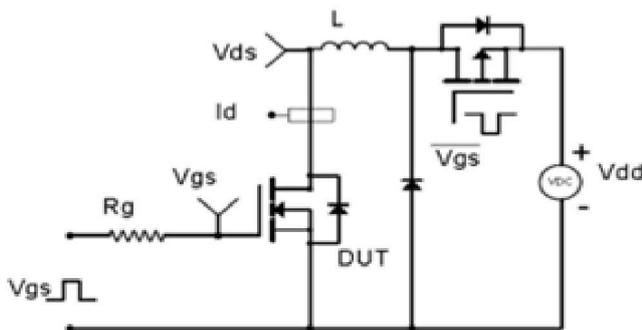
Gate Charge Test Circuit & Waveform



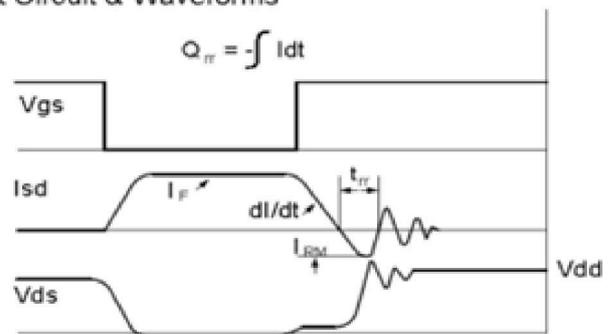
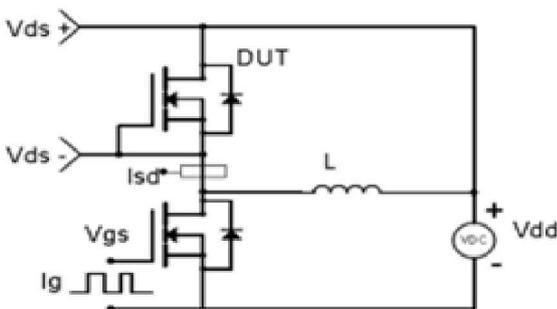
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



**Typical Performance Characteristics**

Fig.1 Power Dissipation Derating Curve

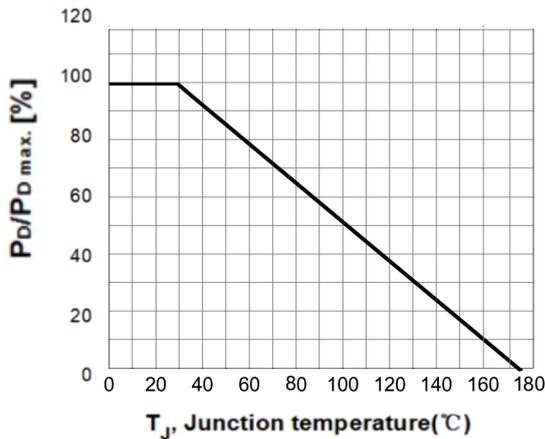


Fig.2 Avalanche Energy Derating Curve vs. Junction Temperature

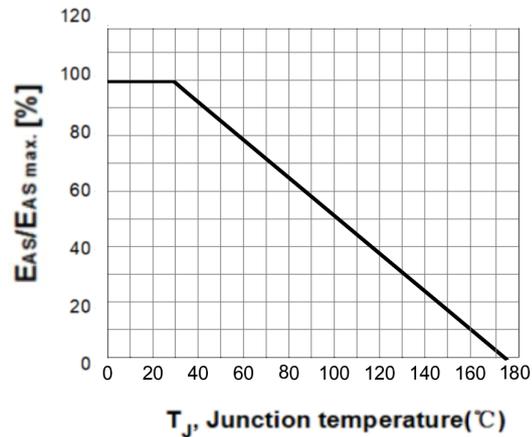


Fig.3 Typical Output Characteristics

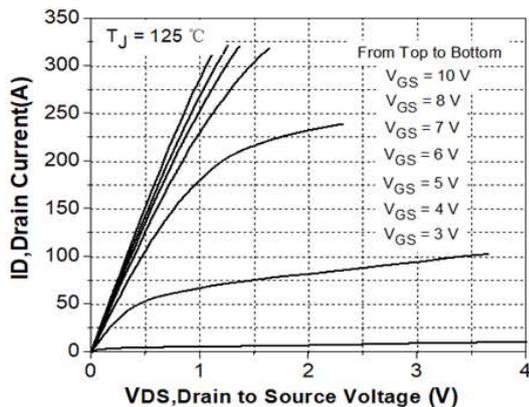


Fig. 4 Transconductance vs. Drain Current

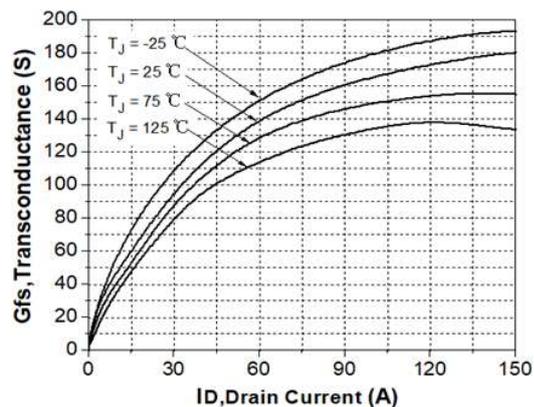


Fig.5 Typical Transfer Characteristics

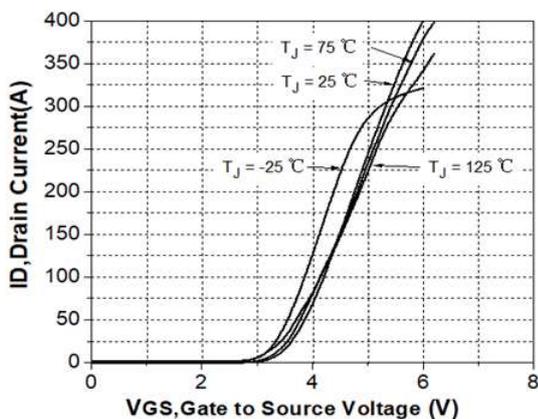


Fig. 6 On-Resistance vs. Drain Current @-25°C

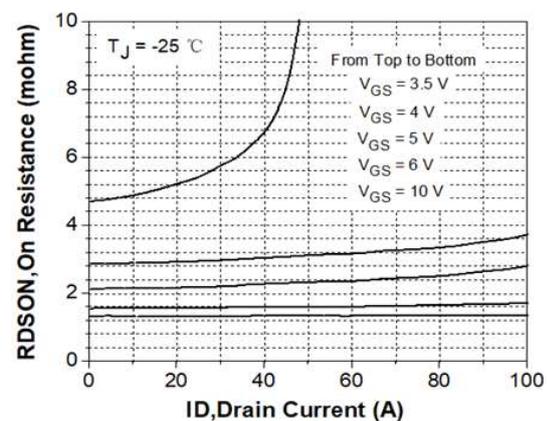


Fig.7 On-Resistance vs. Drain Current @25°C

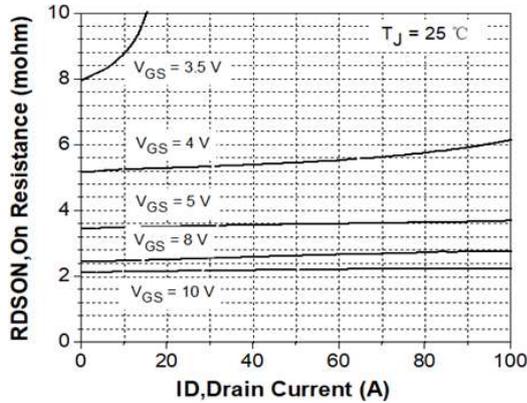


Fig. 8 On-Resistance vs. Drain Current @125°C

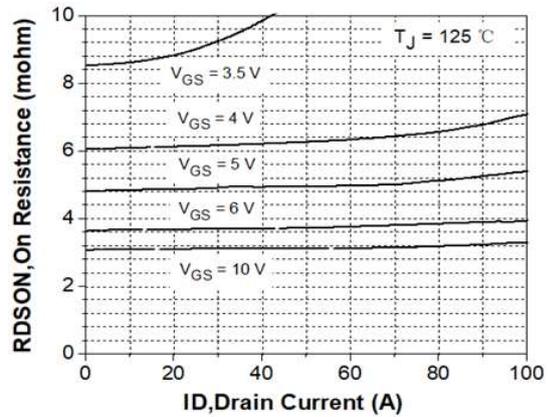


Fig.9 Typical Capacitance vs. Drain Source Voltage

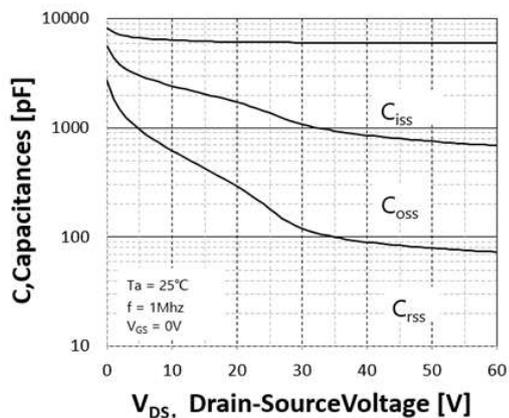


Fig.10 Dynamic Input Characteristics

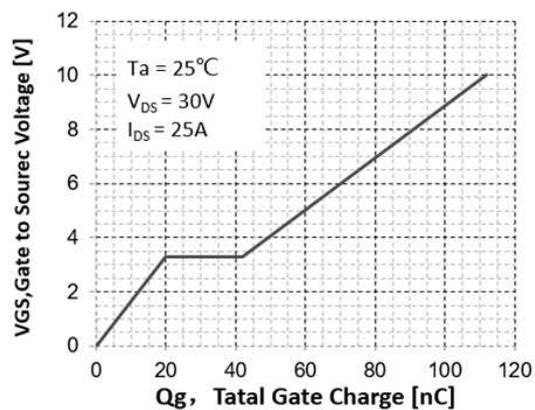


Fig.11 Breakdown Voltage vs. Junction Temperature

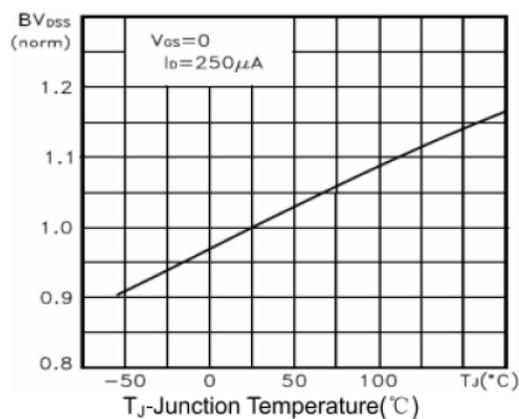


Fig. 12 Gate Threshold Voltage vs. Junction Temperature

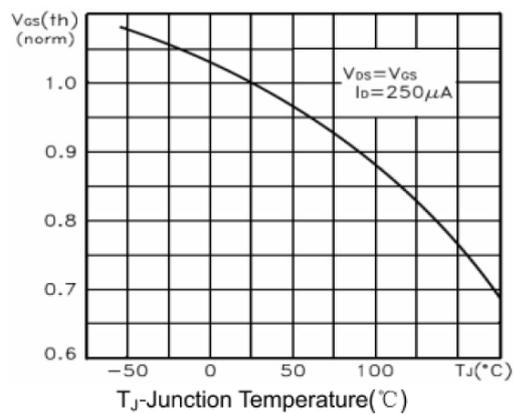


Fig.13 On-Resistance Variation vs. Junction Temperature

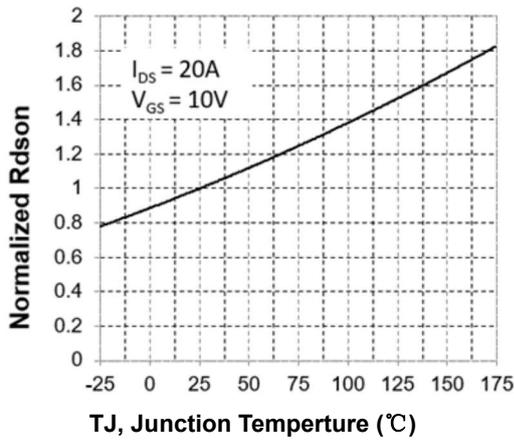


Fig.14 Body Diode Forward Voltage vs. Reverse Drain Current

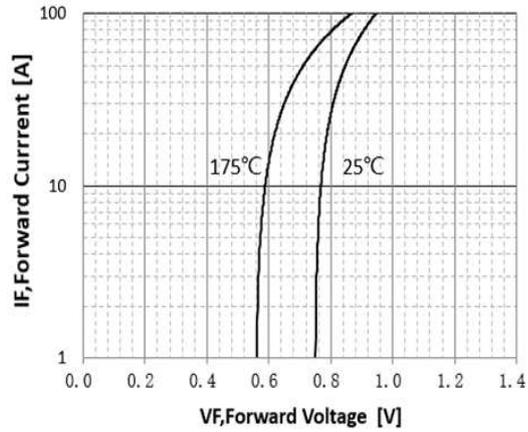


Fig.15 Safe Operating Area

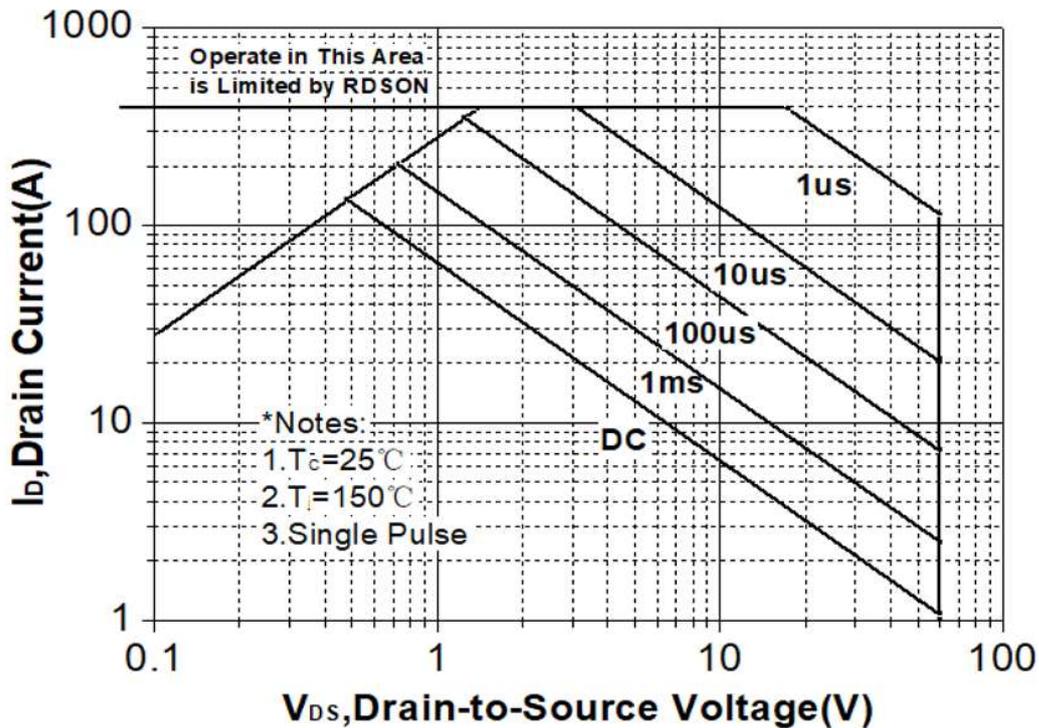
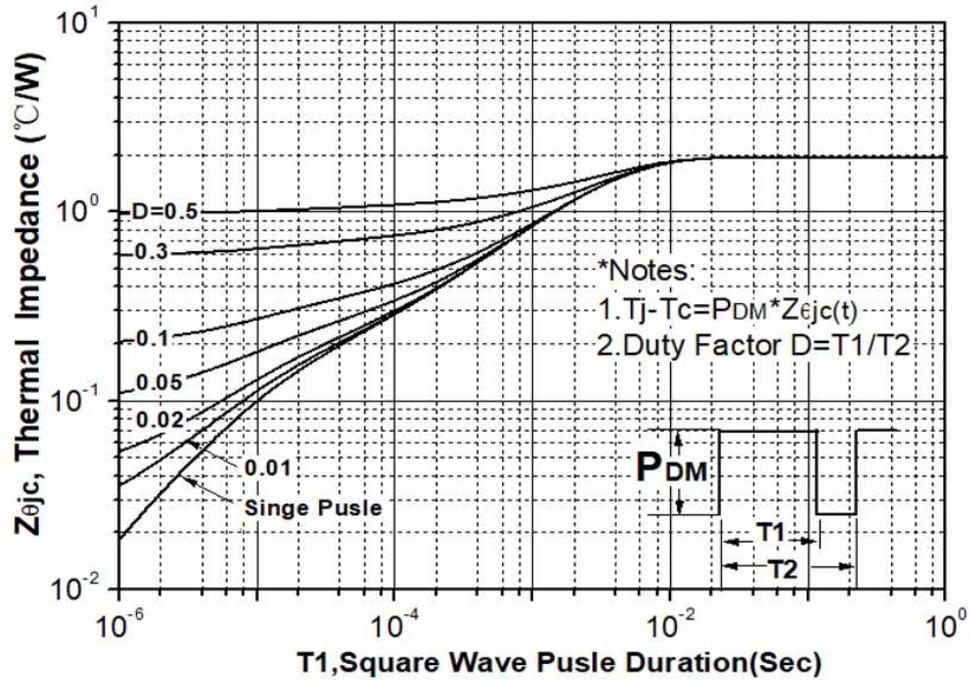
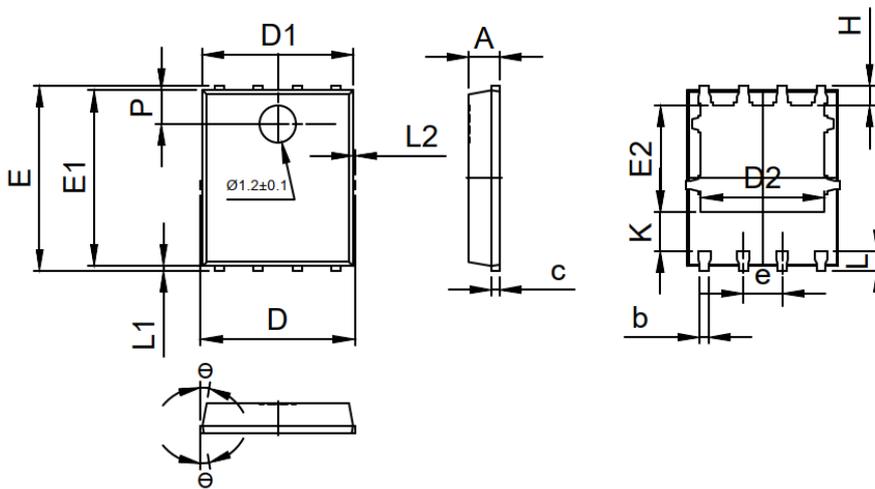


Fig.16 Transient Thermal Response Curve



**APG022N06G-AU**  
**N-Channel Enhancement Mosfet**

**PDFN5X6 Package Information**



SYMBOL	MIN	NOM	MAX
A	0.90	1.00	1.10
b	0.25	0.30	0.35
c	0.21	0.25	0.34
D	-	-	5.10
D1	4.80	4.90	5.00
D2	3.91	4.01	4.11
e	1.27 BSC		
E	5.90	6.00	6.10
E1	5.70	5.75	5.80
E2	3.375	3.475	3.575
H	0.55	0.65	0.75
K	1.20	-	-
L	0.55	0.65	0.75
L1	0.05	0.15	0.25
L2	-	-	0.12
$\theta$	8°	10°	12°
P	1.00	1.10	1.20